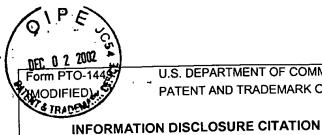
Page 1 of 1 Form PTO-1449 U.S. DEPARTMENT OF COMMERCE ATTY. DOCKET NO. SERIAL NO. (MODIFIED) PATENT AND TRADEMARK OFFICE 039153-0405 (F0945) 09/820,143 APPLICANT INFORMATION DISCLOSURE CITATION Uzodinma Okoroanyanwu et al. **FILING DATE GROUP ART UNIT** (Use several sheets if necessary) 03/28/2001 2878 **U.S. PATENT DOCUMENTS DOCUMENT EXAMINER** FILING DATE SUB-REF DATE CLASS INITIAL NUMBER **CLASS APPROPRIATE** M.E. **A1** 6,197,687 3/06/2001 Buvnoski M.E. A2 5,994,225 11/30/99 Liu et al. А3 5,876,903 3/02/99 Ng et al. 5,468,595 A4 11/21/1995 Livesay **FOREIGN PATENT DOCUMENTS** TRANSLATION DOCUMENT SUB-REF DATE COUNTRY CLASS NUMBER CLASS YES NO OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.) Chiong K.G. et al. "Resist Contrast Enhancement in High Resolution Electron Beam Lithography", Journal of J.E **A5** Vacuum Science and Technology: Part B, American Institute of Physics, New York, US, vol. 7, no. 6. Patent Abstracts of Japan, vol 1999, no. 09, 30 July 1999 (1999-07-30) & JP 11 097328 A (Toshiba Corp), 9 **A6** April 1999 (1999-04-09) abstract **EXAMINER DATE CONSIDERED** M. El-Shammon 7,25,02 EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include any copy of this form with next

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